

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of: Grise et al.

Docket No.: BUR920040061US1

Serial No.: 10/711,075

Art Unit: 2138

Filed: August 20, 2004

Examiner: TABONE JR, JOHN J

Title: **FUNCTIONAL FREQUENCY TESTING OF INTEGRATED CIRCUITS**

---

Honorable Commissioner for Patents  
P. O. Box 1450  
Alexandria, VA 22313-1450

**OFFICE ACTION RESPONSE**

This communication is in response to the Office Action mailed December 20, 2006.